



**Begins**

Oct 1, 2003 at 7:00 am

**Ends**

Oct 3, 2003 at 5:00 pm

**Location**

**Renaissance Seattle Hotel**  
515 Madison Street  
Seattle, WA  
98104  
USA

# The IEEE/CPMT 2003 Workshop on Accelerated Stress Testing

# ASTR 2003

**Hosted By**

[IEEE/CPMT TC-ASTR](#) and  
Technically co-sponsored by  
[IEEE Reliability Society](#)

Over the last few years, Accelerated Stress Testing (AST) has been embraced by an ever widening array of worldwide companies seeking to reconcile the need for the highest quality product with the necessary push for early time-to-market. The purpose of the AST Workshop is to share ideas on better ways of accelerating and detecting hidden defects, flaws, and weaknesses in electronic and electro-mechanical hardware that would result in failures during usage. These techniques are focused on testing electronic hardware to destruction limits and root cause investigation to determine the physics-of-failure. The goal of AST is to produce mature products at market introduction and, in making it robust, the product can be screened for manufacturing defects with high combined stresses (beyond end-use specifications) for shorter lengths of time.

**Name:**

\_\_\_\_\_

**Topics:** Advanced Approaches to AST, Electrodynamic vs. Repetitive Shock Vibration, Reliability Improvement Techniques, AST Data Collection / Analysis, Failure Analysis Techniques and Examples, Reliability Simulation and Modeling, Application of Physics of Failure Techniques, Stress Screening Techniques, AST Case Studies, including stress profiles, Stress other than temperature & vibration, Functional test During Stress Testing, AST Results on New Technologies

**Address:**

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**TUTORIALS:** The all day tutorial program will be held on the first day of the Workshop and features well respected experts sharing their experiences and hard learned lessons. Two parallel sessions, Basic AST and Advanced AST Subjects, will ensure that experienced practitioners as well as those who are just entering the field will find useful and interesting presentations.

**IEEE Member #**

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**e-mail:**

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For more information, visit:

ASTR 2003 -- <http://www.ewh.ieee.org/soc/cpmt/tc7/ast2003/index.html>

CPMT TC-ASTR -- <http://www.ewh.ieee.org/soc/cpmt/tc7/index.html>

IEEE Reliability Society -- <http://www.ewh.ieee.org/soc/rs/index.html>

**Phone:**

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**Send payment in US\$ to:**

**François Lafleur, Acoustique et vibrations  
CIRQ (Centre de recherche industrielle du Québec)  
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_____	<b>IEEE member - after Sept 24</b>	<b>\$ 440.00</b>	\$ _____
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